Untertürkheimer Straße 6-10. **RSC-Laboratory**

D-66117 Saarbrücken

Phone: +49 (0) 681-598-0 Fax: -9075





Accredited testing-laboratory

DAR registration number: DGA-PL-176/94-D1

Federal Motor Transport Authority (KBA) DAR registration number: KBA-P 00070-97

Recognized by the Federal Communications Commission Anechoic chamber registration no.: 90462 (FCC) Anechoic chamber registration no.: 3462C-1 (IC) **Certification ID: DE 0001 Accreditation ID: DE 0002**

Accredited Bluetooth[®] Test Facility (BQTF)
The Bluetooth word mark and logos are owned by the Bluetooth SIG,

Inc. and any use of such marks by Cetecom ICT is under license

Test report no. : 1-2222-01-02/10

Type identification: Phonak Ambra 312 UZ

Applicant : Phonak AG

Test standards : ETSI EN 300 330-1 V1.5.1

ETSI EN 300 330-2 V1.3.1

2010-05-19 Page 1 of 46

Test report no.: 1-2222-01-02/10



Table of contents

1	Gener	al information	3
	1.1 No	tes	3
		sting laboratory	
	1.3 De	tails of applicant	4
	1.4 Ap	plication details	4
2	Test s	tandard/s	5
3	Techn	ical tests	6
	3.1 De	tails of manufacturer	6
	3.1.1	Test item	
	3.1.2	Extreme conditions testing values	6
4	Summ	ary of Measurement Results and list of all performed test cases	7
5	RF me	asurement testing	8
	5.1 De	scription of test set-up	8
	5.1.1	Radiated measurements	
	5.1.2	Conducted measurements	
		ferenced documents	
		ditional comments	
		ansmitter Test Results	
	5.4.1	H-Field strength Subclause 7.2	
	5.4.2	Permitted range of operating frequencies Subclause 7.3	
	5.4.3	Conducted spurious emissions (<30 MHz - Product class 3 only)Subclause 7.4.2	
	5.4.4	Transmitter spurious emission radiated (< 30 MHz) Subclause 7.4.3	
	5.4.5 5.4.6	Transmitter spurious emission radiated (≥ 30 MHz) Subclause 7.4.4	
		Duty cycle Subclause 7.5	
	5.5 Ke	Adjacent channel selectivity-in band Subclause 8.1	
	5.5.2	Blocking or desensitization Subclause 8.2	
	5.5.3	Receiver spurious emissions radiated Subclause 8.3	
6	Test e	quipment and ancillaries used for tests	29
7	Photo	graphs of the Test Set-up	31
8		granhs of the EUT	35

Test report no.: 1-2222-01-02/10



1 General information

1.1 Notes

The test results of this test report relate exclusively to the test item specified in 3.1.1. The CETECOM ICT Services GmbH does not assume responsibility for any conclusions and generalisations drawn from the test results with regard to other specimens or samples of the type of the equipment represented by the test item. The test report may only be reproduced or published in full. Reproduction or publication of extracts from the report requires the prior written approval of the CETECOM ICT Services GmbH.

Test laboratory manager:

2010-05-19	Marco Bertolino	
Date	Name	Signature

Technical responsibility for area of testing:

2010-05-19	Stefan Bös		
Date	Name	Signature	

2010-05-19 Page 3 of 46

Test report no.: 1-2222-01-02/10



1.2 Testing laboratory

CETECOM ICT Services GmbH

Address: Untertürkheimer Straße 6 - 10

66117 Saarbrücken

Germany

 Phone:
 + 49 681 5 98 - 0

 Fax:
 + 49 681 5 98 - 9075

 e-mail:
 info@ICT.cetecom.de

 Internet:
 http://www.cetecom-ict.de

State of accreditation: The test laboratory (area of testing) is accredited according to

DIN EN ISO/IEC 17025

DAR registration number: DGA-PL-176/94-D1

Accredited by: Federal Motor Transport Authority (KBA)
DAR registration number: KBA-P 00070-97

Testing location, if different from CETECOM ICT Services GmbH:

Name : Street : Town : Country : Phone : Fax :

1.3 Details of applicant

Name: Phonak AG

Street: Laubisrütistrasse 28

Town: 8712 Stäfa Country: Schweiz

Telephone: -/-

Fax: +41 (0) 58 928 20 11

Contact: Valentina Shcherba

E-mail: valentina.shcherba@phonak.com

Telephone: +41 (0) 58 928 01 01

1.4 Application details

Date of receipt of order: 2010-04-29

Date of receipt of test item: 2010-05-11

Date of start test: 2010-05-11

Date of end test: 2010-05-19

Persons(s) who have been

present during the test: Mr. Christof Rüegg

2010-05-19 Page 4 of 46

Test report no.: 1-2222-01-02/10



2 Test standard/s

ETSI EN 300 330-1 V1.5.1	2006-04	Electromagnetic compatibility and Radio spectrum Matters (ERM);Short Range Devices (SRD); Radio equipment in the frequency range 9 kHz to 25 MHz and inductive loop systems in the frequency range 9 kHz to 30 MHz Part 1: Technical characteristics and test methods
ETSI EN 300 330-2 V1.3.1	2006-04	Electromagnetic compatibility and Radio spectrum Matters (ERM);Short Range Devices (SRD); Radio equipment in the frequency range 9 kHz to 25 MHz and inductive loop systems in the frequency range 9 kHz to 30 MHz Part 2: Harmonized EN under article 3.2 of the R&TTE Directive

2010-05-19 Page 5 of 46

Test report no.: 1-2222-01-02/10



3 Technical tests

3.1 Details of manufacturer

Name:	Phonak AG
Street:	Laubisrütistrasse 28
Town:	8712 Stäfa
Country:	Schweiz

3.1.1 Test item

Kind of test item	:	Hearing Aid with 10.6 MHz radio interface
Type identification	:	Phonak Ambra 312 UZ
S/N serial number		Phonak WiMo 2030 ITC 26UA L_035
3/10 Serial Humber	•	Phonak WiMo 2030 ITC 26UA R_034
HW hardware status	:	WH2X
SW software status	:	0.3.2.0
Frequency Band	:	10.2 MHz – 11 MHz
Frequencies of the EUT	:	10.6 MHz
Number of channels	:	1
Type of Modulation	:	FSK – F1D inductive
Channel separation	:	Not mandatory \rightarrow one channel only!
Antenna		Integrated ferrite coil antenna \rightarrow for more information, please take a
Antenia		look at sub-clause 8 – photos of the EUT
Product Class	:	1
Duty cycle Class	:	Class 4 - up to 100%
Power Supply	:	1.3 V DC by Zinc-Air battery
Temperature Range	:	0°C to +35 °C

The equipment is compliant to recommendation CEPT/ERC/REC 70-03, Annex 9, Inductive Applications

3.1.2 Extreme conditions testing values

Description	Shortcut	Unit	Value
Nominal Temperature / humidity	T_{nom}	°C / %	+20 / 50
Low Temperature	T_{low}	°C	0
High Temperature	T_{high}	°C	+35
Nominal Power Source	V_{nom}	V	1.3
Low Power Source	V_{low}	V	1.1
High Power Source	$V_{ m high}$	V	1.4

Type of power source: DC by Zinc-Air battery

Deviations from these values are reported in chapter 2

2010-05-19 Page 6 of 46

Test report no.: 1-2222-01-02/10



4 Summary of Measurement Results and list of all performed test cases

\boxtimes	1	No deviations from	the	technical	specifications	were	ascertained
-------------	---	--------------------	-----	-----------	----------------	------	-------------

☐ There were deviations from the technical specifications ascertained

TC identifier	Description	verdict	date	Remark
RF-Testing	ETSI EN 300 330 V1.5.1 (2006-04)	Passed	2010-05-19	-/-

Test Specification Clause	Test Case	temperature conditions	power source voltages	Pass	Fail	Not applicable	Not performed
7.2	H-Field strength	Nominal	Nominal	Yes			
7.3	Permitted range of operating frequencies	Nominal	Nominal	Yes			
7.4.2 (class 3 only)	Conducted spurious emissions (<30 MHz)	Nominal	Nominal			Yes	
7.4.3	Transmitter spurious emission radiated (< 30 MHz)	Nominal	Nominal	Yes			
7.4.4.1	Transmitter spurious emission radiated (≥ 30 MHz)	Nominal	Nominal	Yes			
7.5	Duty cycle	Nominal	Nominal	Yes			
8.1 (class 1 only)	Adjacent channel selectivity- in band	Nominal	Nominal			Yes	
8.2 (class 1 & 2)	Blocking or desensitization	Nominal	Nominal			Yes	
8.3	Receiver spurious emissions radiated	Nominal	Nominal	Yes			

2010-05-19 Page 7 of 46



5 RF measurement testing

5.1 Description of test set-up

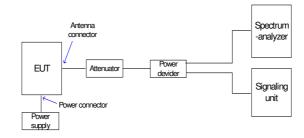
5.1.1 Radiated measurements

The radiated emissions from the EUT are performed in a fully anechoic chamber. The EUT is placed on a non conductive turntable. The EUT is powered with nominal voltage. The signalling is performed either from outside the chamber with a signalling unit (AP or other) by air link using signalling antenna or directly by special software from the customer.

Shielded anechoic chamber / C Signaling antenna antennas amplifier turntable Signaling for EUT spectrum -analyzer

5.1.2 Conducted measurements

The EUT's RF signal is coupled out by the antenna connector which is supplied by the manufacturer. The signal is first 10 dB attenuated before it is power divided (~6 dB loss per branch). One of the signal paths is connected to the signalling unit (AP or other), the other one is connected to the spectrum analyzer. The specific losses for both signal paths are first checked within a calibration. The measurement readings on the signalling unit/spectrum analyzer are corrected by the specific test set-up loss. The attenuator, power divider, signalling unit and the spectrum analyzer are impedance matched on 50 Ohm. If special software is used, there is no power divider necessary.



2010-05-19 Page 8 of 46

Test report no.: 1-2222-01-02/10



5.2 Referenced docume	nts
-----------------------	-----

None

5.3 Additional comments

None

2010-05-19 Page 9 of 46

Test report no.: 1-2222-01-02/10



5.4 Transmitter Test Results

5.4.1 H-Field strength

Subclause 7.2

Results:

TEST CONDITIONS		Transmitter field strength (dBμA/m)
T nom V nom		-24.5 dBμA/m @ 10 m (noise floor)
Measure	ment uncertainty	± 3 dB

LIMITS Subclause 7.2.1.3

Frequency range (MHz)	H-field field strength limit (Hf)dBμA/m at 10 m		
0.009 ≤ 0.315	30		
0.009 < f < 0.03	72 or according to note 1		
$0.03 \le f < 0.05975$ $0.06025 \le f < 0.07$ $0.119 \le f < 0.135$	72 at 0.03 MHz descending 3 dB/oct or according to note 1		
$0.05975 \le f < 0.06025$ $0.07 \le f < 0.119$ $0.135 \le f < 0.140$	42		
$0.140 \le f < 0.1485$	37.7		
0.1485 ≤ f < 30	-5 (see note 4)		
0.315 ≤ f < 0.600	-5		
3.155 ≤ f < 3.400	13.5		
7.400 ≤ f < 8.800	9		
10.2 ≤ f < 11.00	9		
$6.765 \le f \le 6.795 \text{ (ISM)}$ $13.553 \le f \le 13.567 \text{ (ISM)}$ $26.957 \le f \le 27.283 \text{ (ISM)}$	42 (see note 3)		
13.553 ≤ f < 13.567	60 (see notes 2 and 3)		
NOTE 1: For the frequency ranges 9 to 70 kHz and 119 to 135 kHz, the following additional restrictions apply to limits above 42 dBµA/m: - for loop coil antennas with an area ≥ 0.16 m² table 4 applies directly; - for loop coil antennas with an area between 0.05 m² and 0.16 m² table 4 applies with a correction factor. The limit is: table value + 10 log (area/0.16 m²); - for loop coil antennas with an area < 0.05 m² the limit is 10 dB below table 4 NOTE 2: For RFID and EAS applications only. NOTE 3: Spectrum mask limit, see annex G NOTE 4: For further information see annex H			

2010-05-19 Page 10 of 46

Test report no.: 1-2222-01-02/10



5.4.2 Permitted range of operating frequencies

Subclause 7.3

Carrier frequencies below 135 kHz:

Carrier frequencies in the range of 135 kHz to 30 MHz:

30 dB below the carrier
15 dB below the carrier

Results:

TEST CONDITIONS			Frequency (kHz)	
T nom	V nom	FL	10378.557	
1 HOIII	v nom	FH	10705.210	
	V min	FL	10420.734	
T min		FH	10741.179	
	V max	FL	10422.645	
		FH	10743.287	
	V	FL	10363.937	
T max	V min	FH	10692.029	
1 max	V mov	FL	10362.525	
	V max		10695.190	
Measurement uncertainty	± 1x	10-7		

Where F_L = Lowest frequency at the appropriate spurious emission level

FH = Highest frequency at the appropriate spurious emission level

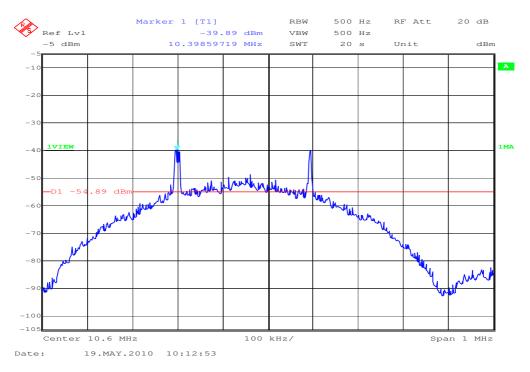
Band edge limits: Lowest measured FL = 10362.525 kHz and Highest measured FH = 10743.287 kHz

2010-05-19 Page 11 of 46

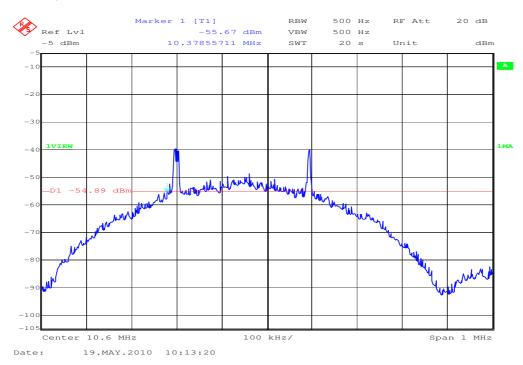
Test report no.: 1-2222-01-02/10



Plot 1: T_{nom} & V_{nom}



Plot 2: T_{nom} & V_{nom} , low side

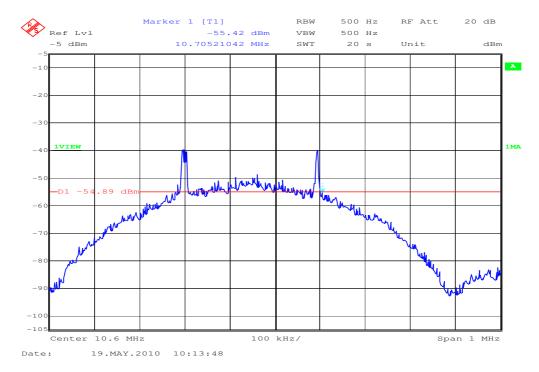


2010-05-19 Page 12 of 46

Test report no.: 1-2222-01-02/10



Plot 3: T_{nom} & V_{nom} , high side



2010-05-19 Page 13 of 46

Test report no.: 1-2222-01-02/10



5.4.3 Conducted spurious emissions (<30 MHz - Product class 3 only)Subclause 7.4.2

Not applicable

Transmitter operating / standby*
* (Delete whichever is inappropriate)

Modulated/Unmodulated*

Results:

	SPURIOUS EMMISSION LEVEL (dBµA/m)							
	Channel 1			Channel 2			Channel 3	
F	BW	Result	F	BW	Result	F	BW	Result
(kHz)	(kHz)	Result	(kHz)	(kHz)	Result	(kHz)	(kHz)	Result
Measu	Measurement uncertainty ± 3dB							

LIMITS Subclause 7.4.2.2

 $(Ic - Is) \ge (Hc - Hs)$

Is is the measured transmitter conducted spurious output current expressed in $dB\mu A$;

Ic is the measured transmitter RF carrier output current expressed in dBµA, see clause 7.2.2.3;

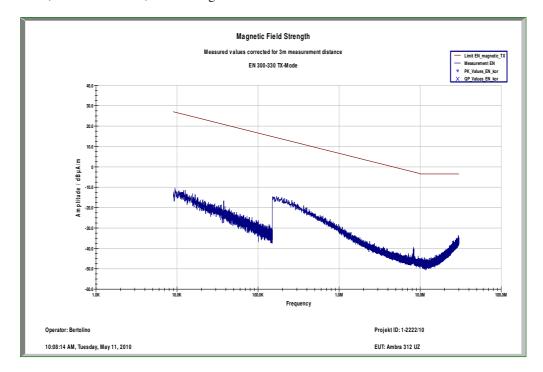
Hc is the radiated limit for the transmitter generated H-field expressed in dBµA/m, see clause 7.2.1.3;

2010-05-19 Page 14 of 46

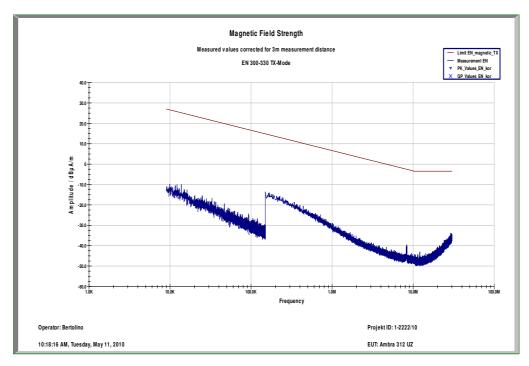


5.4.4 Transmitter spurious emission radiated (< 30 MHz) Subclause 7.4.3

Plot 1: TX mode, 9 kHz – 30 MHz, EUT 1 – right side



Plot 2: TX mode, 9 kHz – 30 MHz, EUT 2 – left side



2010-05-19 Page 15 of 46

Test report no.: 1-2222-01-02/10



Results:

	SPURIOUS EMMISSION LEVEL (dBµA/m)							
Channel 1			Channel 2			Channel 3		
E	EUT 1 / EUT	2						
F	BW	Level	F	BW	Level	F	BW	Level
(kHz)	(kHz)	(dBµA/m)	(kHz)	(kHz)	(dBµA/m)	(kHz)	(kHz)	(dBµA/m)
	No critical peaks detected. All detected emissions are below the limit.							
Measu	Measurement uncertainty				± 3	dB		

LIMIT SUBCLAUSE 7.4.3.2

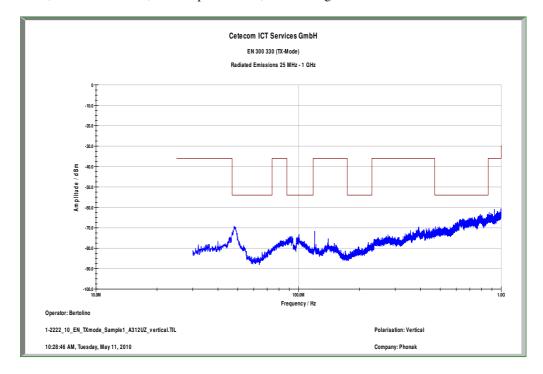
State	Frequency 9 kHz < f < 10 MHz	Frequency 10 MHz < f < 30 MHz
Transmit	27 dBµA/m at 9 kHz descending 3 dB/oct	-3.5 dBµA/m
Standby	5.5 dBµA/m at 9 kHz descending 3 dB/oct	-22 dBµA/m

2010-05-19 Page 16 of 46

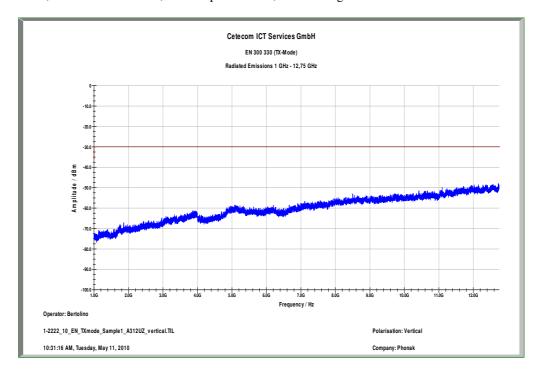


5.4.5 Transmitter spurious emission radiated (≥ 30 MHz) Subclause 7.4.4

Plot 1: TX mode, 30 MHz – 1 GHz, vertical polarisation, EUT 1 – right side



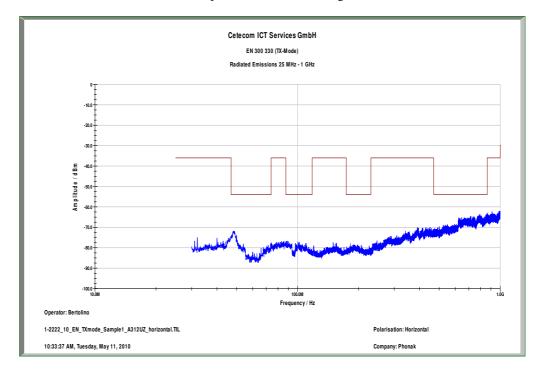
Plot 2: TX mode, 1 GHz – 12.75 GHz, vertical polarisation, EUT 1 – right side



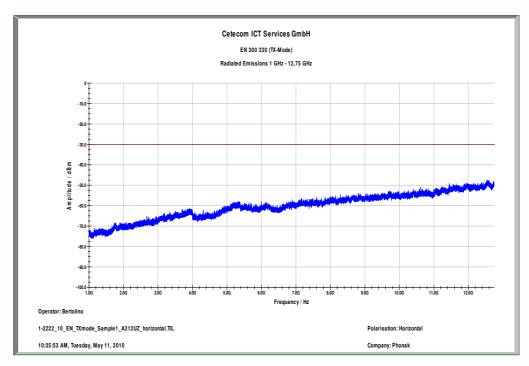
2010-05-19 Page 17 of 46



Plot 3: TX mode, 30 MHz – 1 GHz, horizontal polarisation, EUT 1 – right side



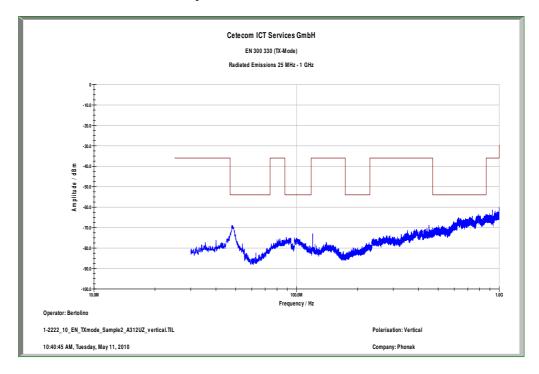
Plot 4: TX mode, 1 GHz – 12.75 GHz, horizontal polarisation, EUT 1 – right side



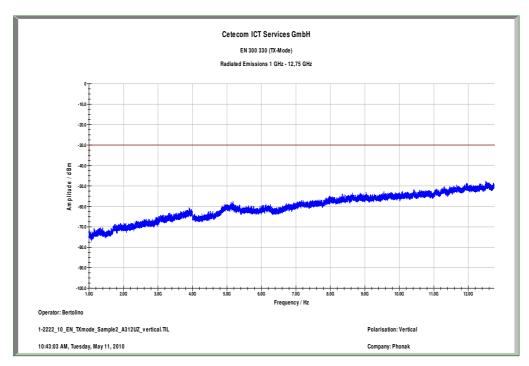
2010-05-19 Page 18 of 46



Plot 5: TX mode, 30 MHz – 1 GHz, vertical polarisation, EUT 1 – left side



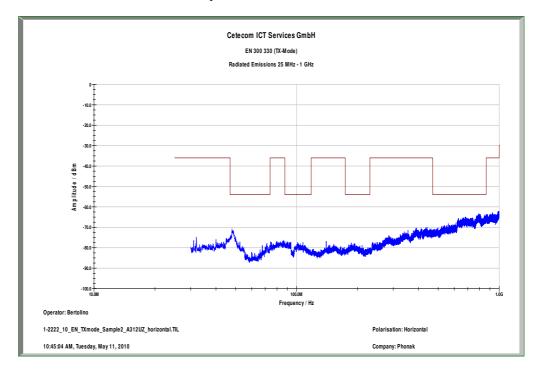
Plot 6: TX mode, 1 GHz – 12.75 GHz, vertical polarisation, EUT 1 – left side



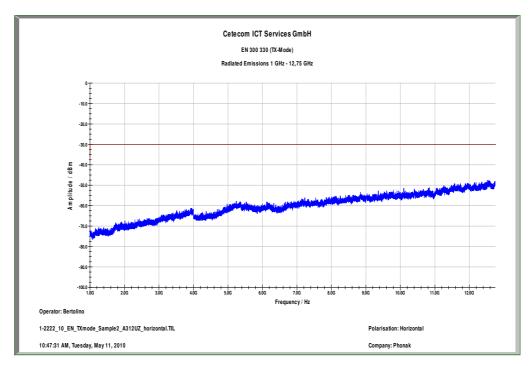
2010-05-19 Page 19 of 46



Plot 7: TX mode, 30 MHz – 1 GHz, horizontal polarisation, EUT 1 – left side



Plot 8: TX mode, 1 GHz – 12.75 GHz, horizontal polarisation, EUT 1 – left side



2010-05-19 Page 20 of 46

Test report no.: 1-2222-01-02/10



Results:

	SPURIOUS EMMISSION LEVEL (nW)							
	Channel 1			Channel 2			Channel 3	
Е	UT 1 / EUT	2						
F	BW	Level	F	BW	Level	F	BW	Level
(MHz)	(kHz)	(nW)	(MHz)	(kHz)	(nW)	(MHz)	(kHz)	(nW)
	al peaks determissions are limit.							
Measur	Measurement uncertainty ± 3dB							

LIMITS Subclause 7.4.4.2

State	47 MHz to 74 MHz 87.5 MHz to 118 MHz 174 MHz to 230 MHz 470 MHz to 862 MHz	Other Frequencies between 30 to 1000 MHz
Transmit	4 nW	250 nW
Standby	2 nW	2 nW

2010-05-19 Page 21 of 46

Test report no.: 1-2222-01-02/10



Duty cycle	Subclause	7.5
Duty Cyclc	Bubliaust	

Results:

Duty cycle Class: 4

LIMITS Subclause 7.5.3

In a period of 1 hour the duty cycle shall not exceed the values

Duty cycle Class	Duty cycle ratio
1	< 0.1 %
2	< 1.0 %
3	< 10 %
4	Up to 100 %

2010-05-19 Page 22 of 46

Test report no.: 1-2222-01-02/10



5.5 Receiver Test Results

5.5.1 Adjacent channel selectivity-in band

Subclause 8.1

Not applicable (Receiver Class 1 only)

This measurement is required where a frequency plan with standard channel spacing is stated.

The measurement shall not be performed if:

- a) The transmitter cannot be switched off and the spacing between the transmit and the receiver frequency is less than ten times the declared receiver 3 dB bandwidth; or
- b) The transmitter and receiver are operating at the same frequency and the transmitter cannot be switched off as the carrier is used as receiver injection signal.(e.g. for homodyne systems).

LIMITS Subclause 8.1.3

Receiver class	Channel spacing ≤ 25 kHz	Channel spacing > 25 kHz
1	60 dB	70 dB

2010-05-19 Page 23 of 46

Test report no.: 1-2222-01-02/10



5.5.2 Blocking or desensitization

Subclause 8.2

Not applicable (Receiver Class 1 & 2 only)

Results:

TEST CONDITIONS			BLOCKING (dBm)	
		Channel 1	Channel 2	Channel 3
T nom	V nom			
Measurement uncertainty			±3dB	

LIMITS Subclause 8.2.3

Receiver		tor B frequency off by a) or b) whicheve (see note 3)	Limit (dB)	
Class	a) per clause 8	3.2.2, indent a)	b) per clause 8.2.2, indent b)	
	fA < 500 kHz	$fA \ge 500 \text{ kHz}$	value of N, see below	
1	For all offset frequencies	For all offset frequencies	2, 4, 8 and 20	Reference Limit (see note 1)
	± 100 kHz	$\pm 500 \text{ kHz}$	2	Reference Limit \times 1/2 (see note 2)
2	$\pm 200 \text{ kHz}$	$\pm 1 \text{ MHz}$	4	Reference Limit \times 2/3 (see note 2)
2	$\pm 300 \text{ kHz}$	$\pm 2 \text{ MHz}$	8	Reference Limit \times 5/6 (see note 2)
	$\pm 500 \text{ kHz}$	± 5 MHz	20	Reference limit, (see note 1)

NOTE 1: Reference limit (Ref) = 30 dB at 9 kHz increasing with 10 dB/decade to 65,2 dB at 30 MHz.

NOTE 2: The limit is a fractional dB value of the reference limit.

NOTE 3: Generator B frequencies below 9 kHz are not specified.

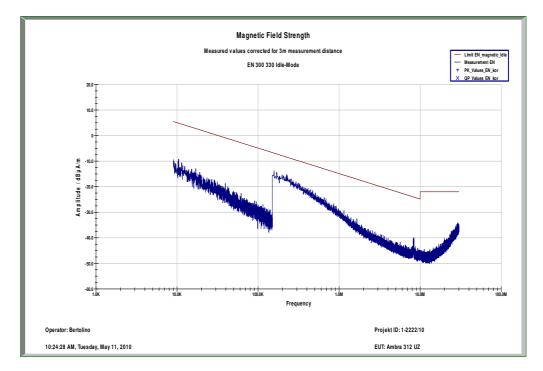
2010-05-19 Page 24 of 46



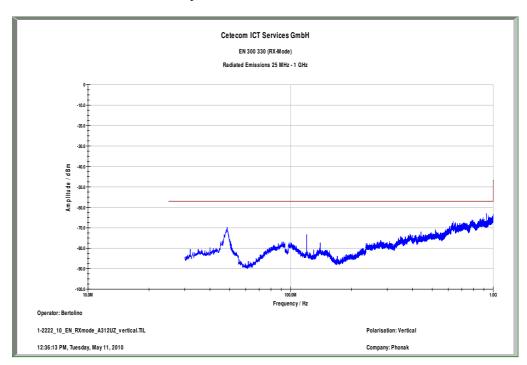
5.5.3 Receiver spurious emissions radiated

Subclause 8.3

Plot 1: RX mode, 9 kHz – 30 MHz, EUT 1 / EUT 2



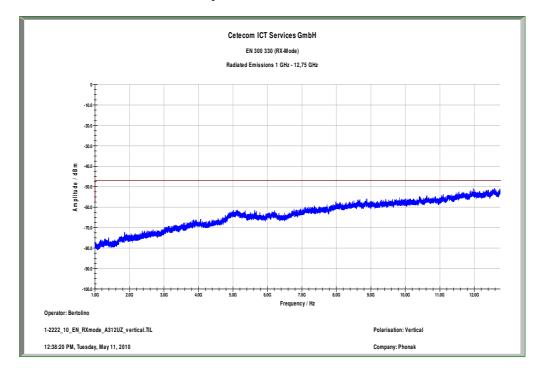
Plot 2: RX mode, 30 MHz – 1 GHz, vertical polarisation, EUT 1 / EUT 2



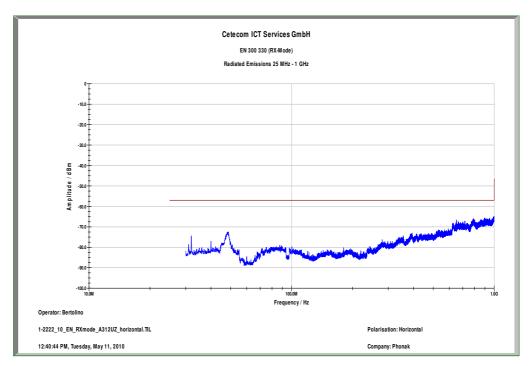
2010-05-19 Page 25 of 46



Plot 3: RX mode, 1 GHz – 12.75 GHz, vertical polarisation, EUT 1 / EUT 2



Plot 4: RX mode, 30 MHz – 1 GHz, horizontal polarisation, EUT 1 / EUT 2

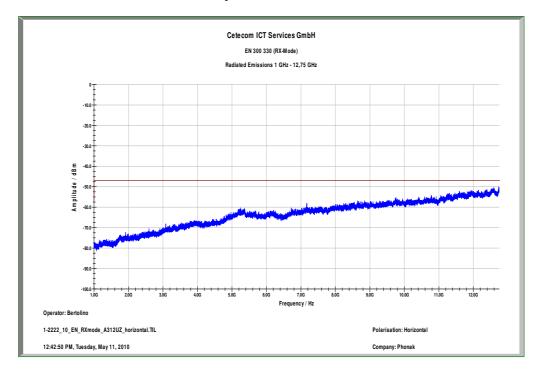


2010-05-19 Page 26 of 46

Test report no.: 1-2222-01-02/10



Plot 5: RX mode, 1 GHz – 12.75 GHz, horizontal polarisation, EUT 1 / EUT 2



2010-05-19 Page 27 of 46

Test report no.: 1-2222-01-02/10



Results:

SPURIOUS EMMISSION LEVEL (nW)										
Idle Mode			-/-			-/-				
					T		I			
F	BW	p	F	BW	p	F	BW	p		
No criti detected	No critical peaks detected. All detected emissions are below the limit.									
Measurement uncertainty		± 3dB								

Where F = Frequency of spurious (MHz)

BW = Measurement receiver bandwidth (kHz)

p = Level of spurious $(\mu W, nW)$

LIMITS Subclause 8.3.3

State	Frequency 9 kHz < f < 10 MHz	Frequency $10 \text{ MHz} < f < 30 \text{ MHz}$
Standby	5.5 dBµA/m at 9 kHz descending 3 dB/oct	-22 dBμA/m

2010-05-19 Page 28 of 46

Test report no.: 1-2222-01-02/10



6 Test equipment and ancillaries used for tests

In order to simplify the identification of the equipment used at each specific test, each item of test equipment and ancillaries are provided with an identifier or number in the equipment list below.

Typically, the calibrations of the test apparatus are commissioned to and performed by an accredited calibration laboratory. The calibration intervals are determined in accordance with the DIN EN ISO/IEC 17025. In addition to the external calibrations, the laboratory executes comparison measurements with other calibrated test systems or effective verifications. Weekly chamber inspections and range calibrations are performed. Where possible, rf-generating and signalling equipment as well as measuring receivers and analyzers are connected to an external high-precision 10 MHz reference (GPS-based or rubidium frequency standard).

No.	Labor / Item	Equipment	Type	Manufact.	Serial No.	INV. No Cetecom	Kal. Art	Last Calibra tion	Next Calibra tion
1	n. a.	Double- Ridged Waveguide Horn Antenna 1- 26.5GHz	3115	EMCO	8812- 3088	300001 032	vlKI!	05.03. 2009	05.03. 2011
2	n. a.	Active Loop Antenna	6502	EMCO	2210	300001 015	ne		
3	n. a.	Anechoic chamber System rack		MWB	87400/0 2	300000 996			
4	Spec.A. 2_2e	for EMI measurement solution	85900	HP I.V.	*	300000 222	ne		
5	9	Artificial Mains 9 kHz to 30 MHz, 4 x 25	ESH3-Z5	R&S	828576/ 020	300001 210	Ve	06.01. 2010	06.01. 2012
6	n. a.	Ampere Relais Matrix	3488A	HP Meßtechnik	2719A15 013	300001 156	ne		
7	n. a.	Relais Matrix	PSU	R&S	890167/ 024	300001 168	ne		
8	n. a.	Isolating Transformer Three-Way	RT5A	Grundig	9242	300001 263	ne		
9	n. a.	Power Splitter, 50 Ohm	11850C	HP Meßtechnik		300000 997	ne		
10	n. a.	Switch / Control Unit	3488A WRCG1855/1	HP	2605e08 770	300001 443	ne		
11	n. a.	Band Reject filter	910- 1835/1925- 40/8SS	Wainwright	7	300003 350	ev		
12	n. a.	Band Reject filter	WRCG2400/2 483- 2375/2505- 50/10SS	Wainwright	11	300003 351	ev		
13	n. a.	TILE- Software Emission	Quantum Change, Modell TILE-	EMCO	none	300003 451	ne		

2010-05-19 Page 29 of 46

Test report no.: 1-2222-01-02/10



			ICS/FULL						
14	n. a.	Highpass Filter	WHKX2.9/18 G-12SS	Wainwright	1	300003 492	ev		
15	n. a.	Highpass Filter	WHK1.1/15G- 10SS	Wainwright	3	300003 255	ev		
16	n. a.	Highpass Filter PSA	WHKX7.0/18 G-8SS	Wainwright	18	300003 789	ne		
17	n. a.	Spectrum Analyzer 3 Hz - 26.5 GHz	E4440A	Agilent Technologies	MY4825 0080	300003 812	k	05.08. 2008	05.08. 2010
18	n. a.	MXG Microwave Analog Signal Generator	N5183A	Agilent Technologies	MY4742 0220	300003 813	k	06.08. 2008	06.08. 2010
19	n. a.	RF Filter Section 9kHz - 1GHz TRILOG	N9039A	Agilent Technologies	MY4826 0003	300003 825	vlKI!	19.08. 2008	19.08. 2010
20	n. a.	Broadband Test- Antenna 30 MHz - 3 GHz	VULB9163	Schwarzbeck	371	300003 854	vlKI!	17.12. 2008	17.12. 2010
21	n. a.	Test Receiver	ESH2	R&S	871921/ 095	300002 505	Ve	12.02. 2010	12.02. 2012
22	n. a.	Loop Antenna 9 KHz - 30 MHz	HFH2-Z2	R&S	872096/ 61	300001 824	vlKI!	18.11. 2008	18.11. 2011
23	n. a.	Power Supply	LA30/5GA	Zentro Elektronik	2046	300000 711	NK!		
24	n. a.	Temperature Test Chamber	VT 4002	Heraeus Voetsch	521/837 61	300002 326	Ve	28.05. 2009	28.05. 2011
25	n. a.	Signal Analyzer 20Hz- 26,5GHz- 150 to + 30 DBM	FSIQ26	R&S	835540/ 018	300002 681- 0005	k	07.01. 2010	07.01. 2012

2010-05-19 Page 30 of 46



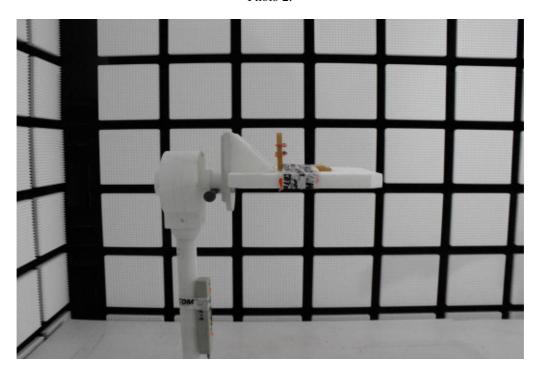
7 Photographs of the Test Set-up

Photo documentation:

Photo 1:



Photo 2:



2010-05-19 Page 31 of 46



Photo 3:



Photo 4:



2010-05-19 Page 32 of 46

Test report no.: 1-2222-01-02/10



Photo 5:



Photo 6:



2010-05-19 Page 33 of 46



Photo 7:

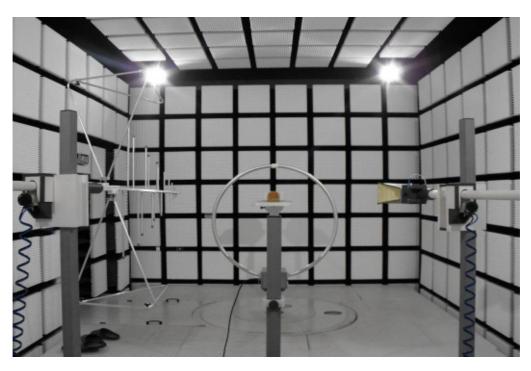


Photo 8:



2010-05-19 Page 34 of 46



8 Photographs of the EUT

Photo documentation: external photos

Photo 1: Sample 1

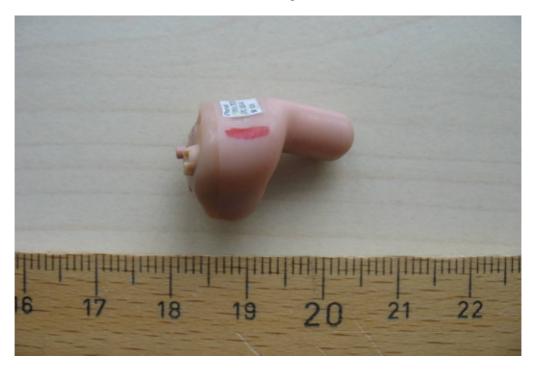


Photo 2: Sample 1



2010-05-19 Page 35 of 46



Photo 3: Sample 1

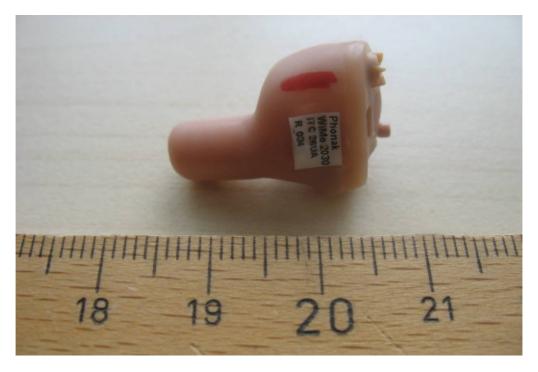


Photo 4: Sample 1



2010-05-19 Page 36 of 46



Photo 5: Sample 1



Photo 6: Sample 2



2010-05-19 Page 37 of 46



Photo 7: Sample 2



Photo 8: Sample 2



2010-05-19 Page 38 of 46



Photo 9: Sample 2



Photo 10: Sample 2



2010-05-19 Page 39 of 46

Test report no.: 1-2222-01-02/10



Photo 11: Sample 2



2010-05-19 Page 40 of 46



Photo documentation: internal photos

Photo 1:

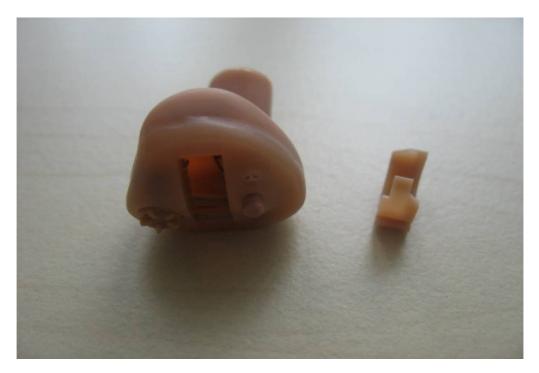


Photo 2:



2010-05-19 Page 41 of 46

Test report no.: 1-2222-01-02/10



Photo 3:



Photo 4:



2010-05-19 Page 42 of 46

Test report no.: 1-2222-01-02/10



Photo 5:

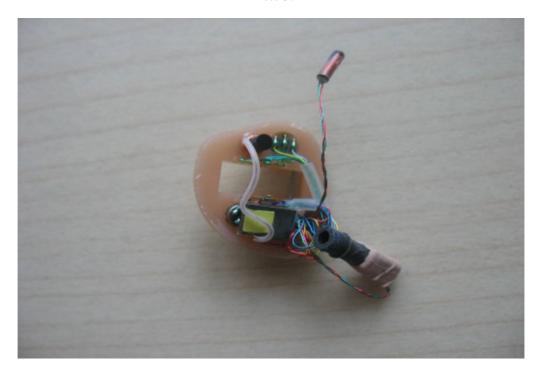
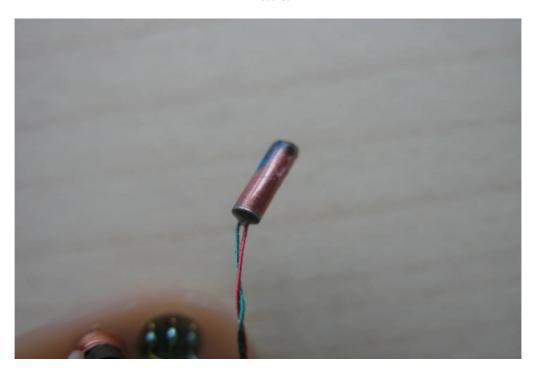


Photo 6:



2010-05-19 Page 43 of 46

Test report no.: 1-2222-01-02/10



Photo 7:

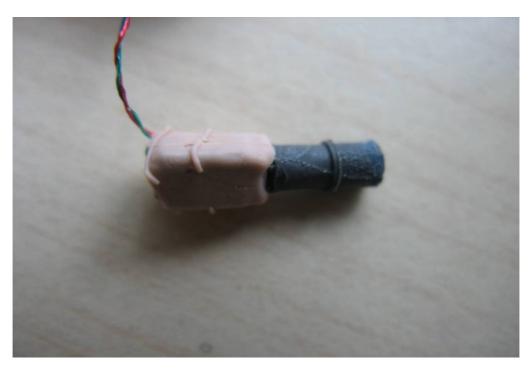
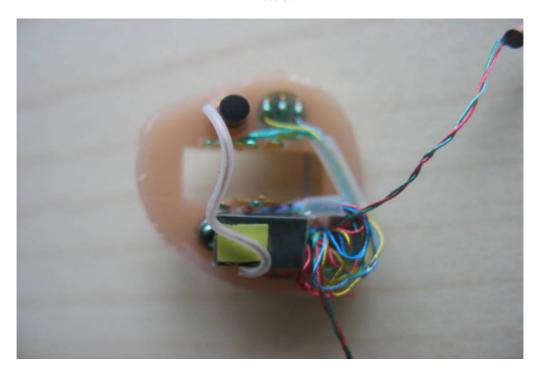


Photo 8:



2010-05-19 Page 44 of 46

Test report no.: 1-2222-01-02/10



Photo 9:

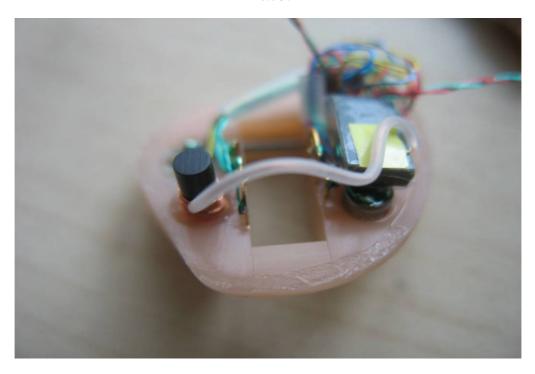
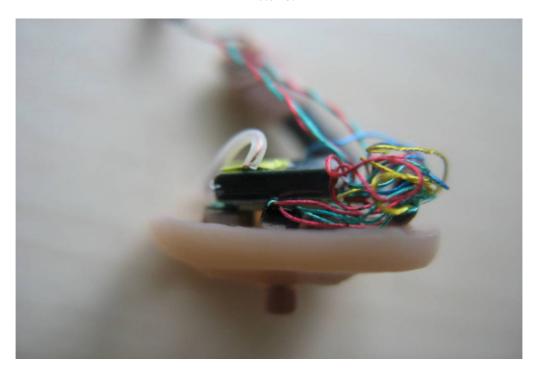


Photo 10:



2010-05-19 Page 45 of 46

Test report no.: 1-2222-01-02/10



Photo 11:

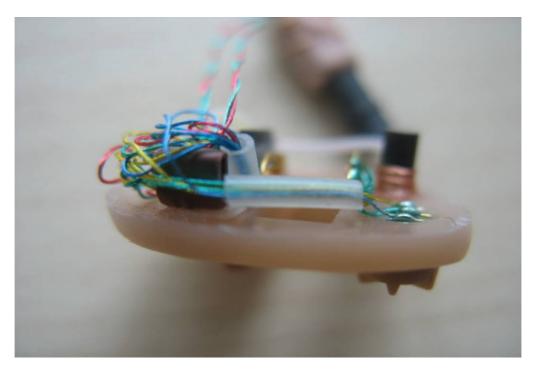
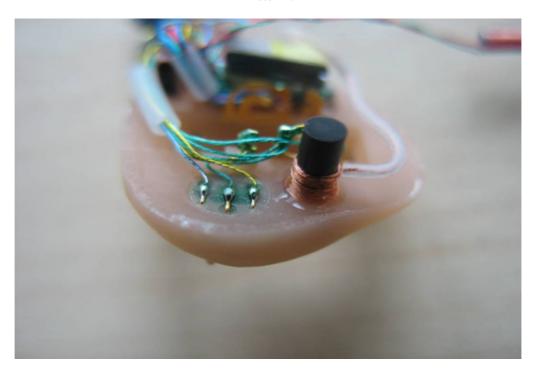


Photo 12:



2010-05-19 Page 46 of 46